

## 60V N-Channel Enhancement Mode MOSFET

### Description

The AP100N06NF uses advanced **APM-SGT II** technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 10V. This device is suitable for use as a Battery protection or in other Switching application.

### General Features

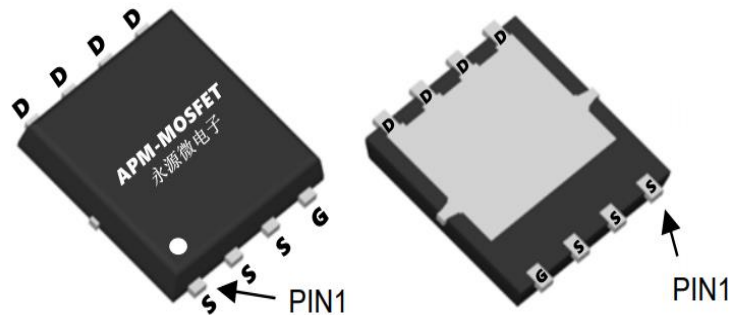
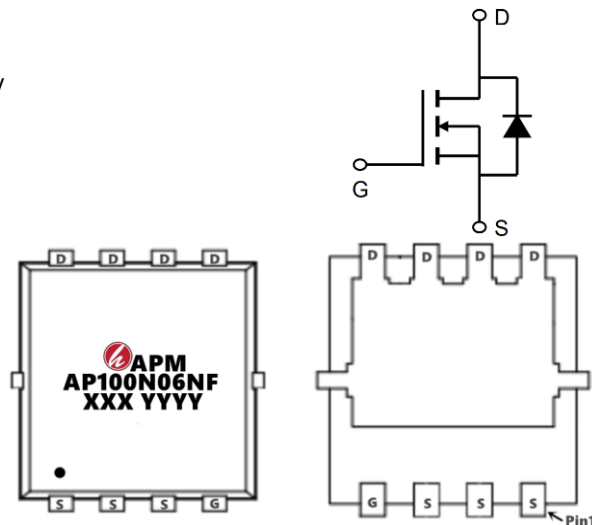
$V_{DS} = 60V$   $I_D = 100A$

$R_{DS(ON)} < 4.5m\Omega$  @  $V_{GS}=10V$  (Type: **3.5mΩ**)

### Application

Battery protection

UPS



### Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP100N06NF	PDFN5*6-8L	AP100N06NF XXX YYYYY	5000

### Absolute Maximum Ratings ( $T_C=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	60	V
$V_{GS}$	Gate-Source Voltage	$\pm 20$	V
$I_D @ T_C=25^\circ C$	Continuous Drain Current <sup>1,6</sup>	100	A
$I_D @ T_C=100^\circ C$	Continuous Drain Current <sup>1,6</sup>	61	A
IDM	Pulsed Drain Current <sup>2</sup>	380	A
EAS	Single Pulse Avalanche Energy <sup>3</sup>	80	mJ
IAS	Avalanche Current	40	A
$P_D @ T_C=25^\circ C$	Total Power Dissipation <sup>4</sup>	73.5	W
TSTG	Storage Temperature Range	-55 to 150	$^\circ C$
$T_J$	Operating Junction Temperature Range	-55 to 150	$^\circ C$
$R_{\theta JA}$	Thermal Resistance Junction-Ambient <sup>1</sup>	51	$^\circ C/W$
$R_{\theta JC}$	Thermal Resistance Junction-Case <sup>1</sup>	1.7	$^\circ C/W$

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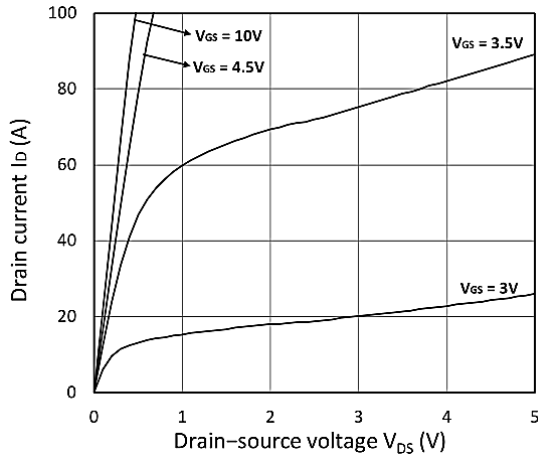
### Electrical Characteristics (T<sub>J</sub>=25°C, unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	65	-	-	V
I <sub>GSS</sub>	Gate-body Leakage Current	V <sub>DS</sub> = 0V, V <sub>GS</sub> = ±20V	-	-	±100	nA
I <sub>DSS</sub>	Zero Gate Voltage Drain Current T <sub>J</sub> =25°C	V <sub>DS</sub> = 65V, V <sub>GS</sub> = 0V	-	-	1	μA
	Zero Gate Voltage Drain Current T <sub>J</sub> =100°C		-	-	100	
V <sub>GS(th)</sub>	Gate-Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	1.2	1.7	2.5	V
R <sub>DS(on)</sub>	Drain-Source On-Resistance <sup>4</sup>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 20A	-	3.5	4.5	mΩ
		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 10A	-	4.8	6.6	
g <sub>fs</sub>	Forward Transconductance <sup>4</sup>	V <sub>DS</sub> = 10V, I <sub>D</sub> = 20A	-	89	-	S
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 30V, V <sub>GS</sub> = 0V, f = 1MHz	-	2180	-	pF
C <sub>oss</sub>	Output Capacitance		-	735	-	
C <sub>rss</sub>	Reverse Transfer Capacitance		-	42	-	
R <sub>g</sub>	Gate Resistance	f = 1MHz	-	1.8	-	Ω
Q <sub>g</sub>	Total Gate Charge	V <sub>GS</sub> = 10V, V <sub>DS</sub> = 30V, I <sub>D</sub> = 20A	-	35	-	nC
Q <sub>gs</sub>	Gate-Source Charge		-	6.6	-	
Q <sub>gd</sub>	Gate-Drain Charge		-	8.4	-	
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>GS</sub> = 10V, V <sub>DD</sub> = 30V, R <sub>G</sub> = 3Ω, I <sub>D</sub> = 20A	-	9.4	-	ns
t <sub>r</sub>	Rise Time		-	8.4	-	
t <sub>d(off)</sub>	Turn-Off Delay Time		-	32.5	-	
t <sub>f</sub>	Fall Time		-	12.5	-	
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> = 20A, dI/dt = 100A/μs	-	50	-	ns
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge		-	20	-	nC
V <sub>SD</sub>	Diode Forward Voltage <sup>4</sup>	I <sub>S</sub> = 20A, V <sub>GS</sub> = 0V	-	-	1.2	V
I <sub>S</sub>	Continuous Source Current	T <sub>C</sub> = 25°C	-	-	100	A

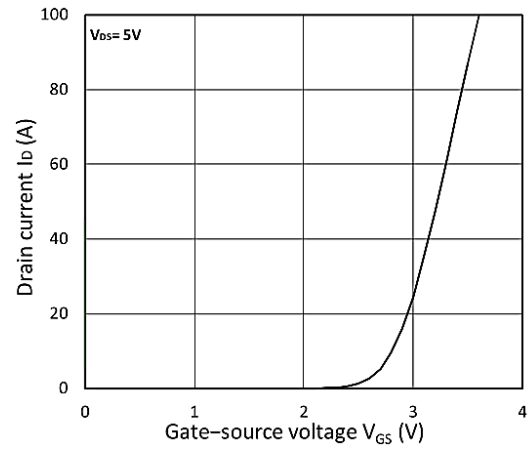
**Note :**

- 1、 The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.
- 2、 The data tested by pulsed , pulse width .The EAS data shows Max. rating .
- 3、 The power dissipation is limited by 175°C junction temperature
- 4、 EAS condition: T<sub>J</sub>=25°C, V<sub>DD</sub>=25V, V<sub>GS</sub>=10V, L=0.1mH, I<sub>AS</sub>=40A
- 5、 The data is theoretically the same as I<sub>D</sub> and I<sub>DM</sub> , in real applications , should be limited by total power dissipation.

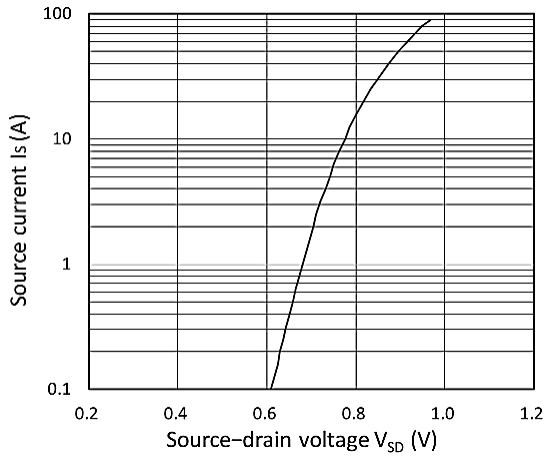
### Typical Characteristics



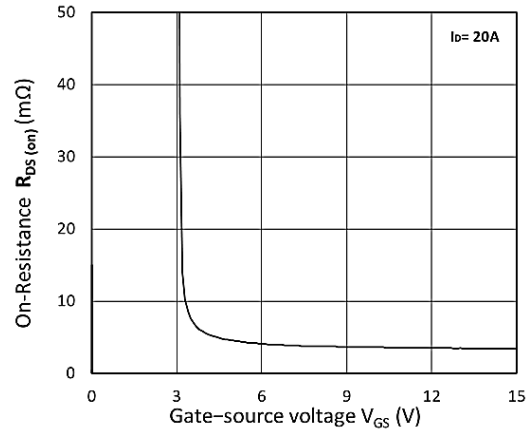
**Figure 1. Output Characteristics**



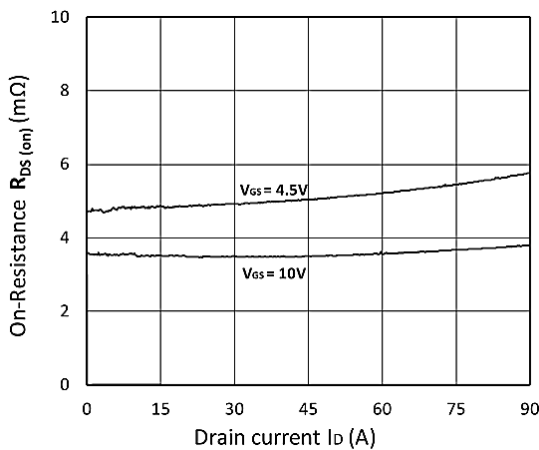
**Figure 2. Transfer Characteristics**



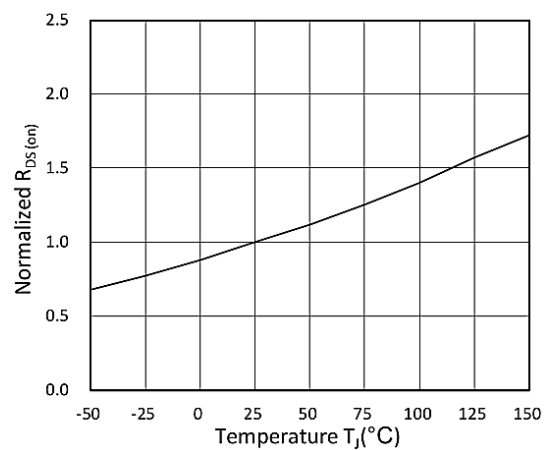
**Figure 3. Forward Characteristics of Reverse**



**Figure 4. RDS(ON) vs. VGS**



**Figure 5. R DS(ON) vs. ID**



**Figure 6. Normalized R DS(on) vs. Temperature**

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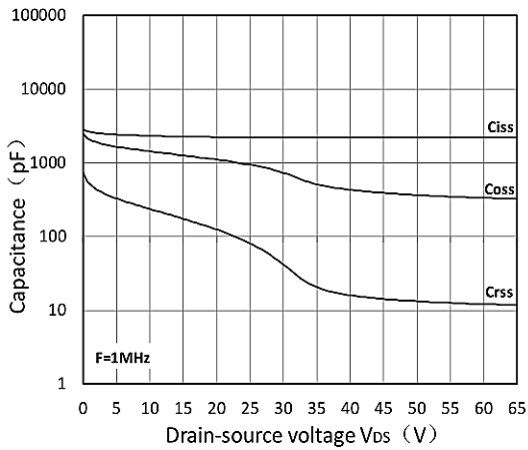


Figure 7. Capacitance Characteristics

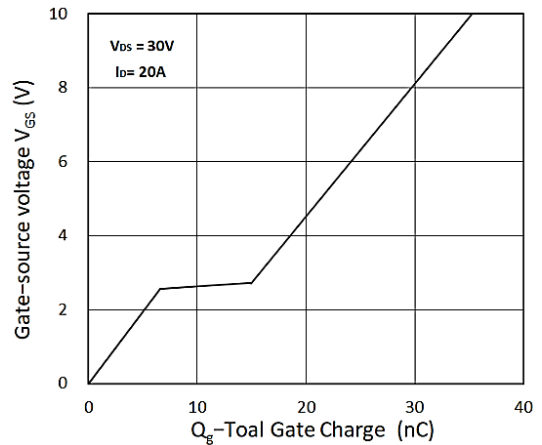


Figure 8. Gate Charge Characteristics

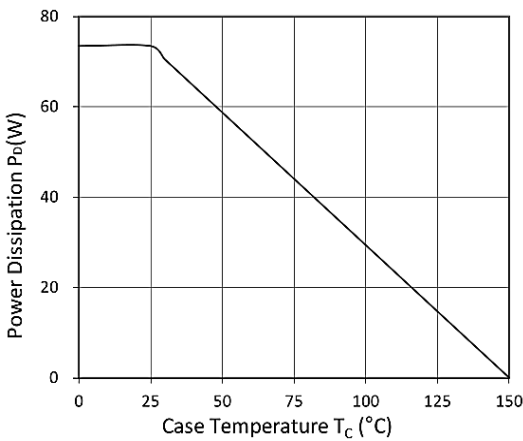


Figure 9. Power Dissipation

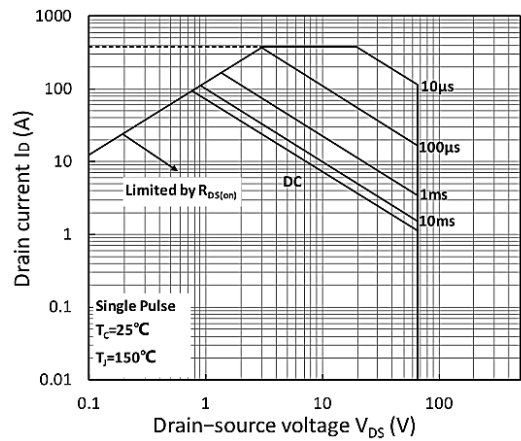


Figure 10. Safe Operating Area

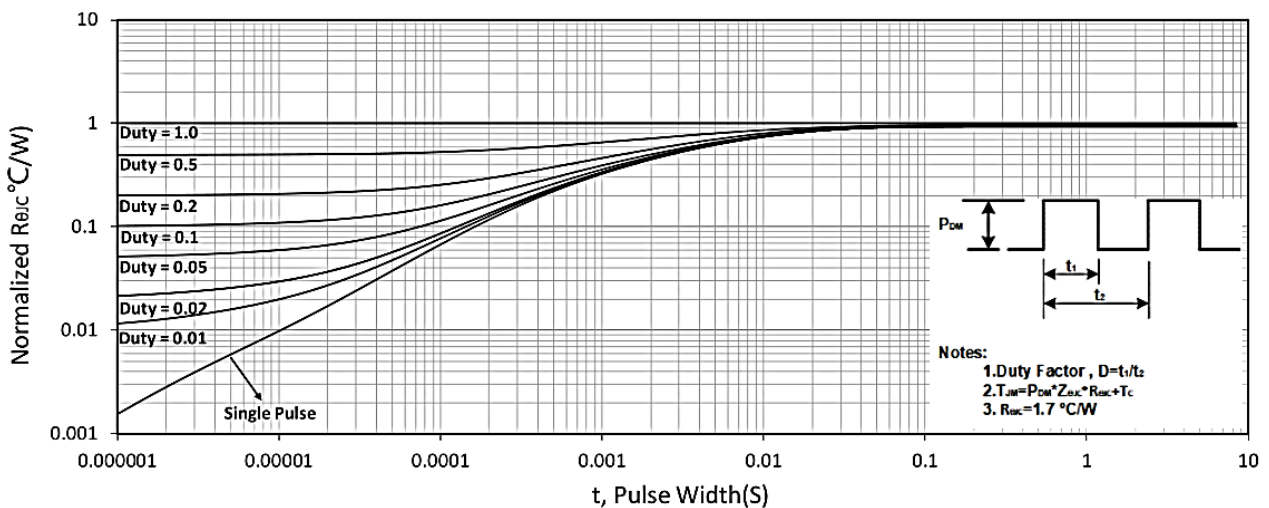
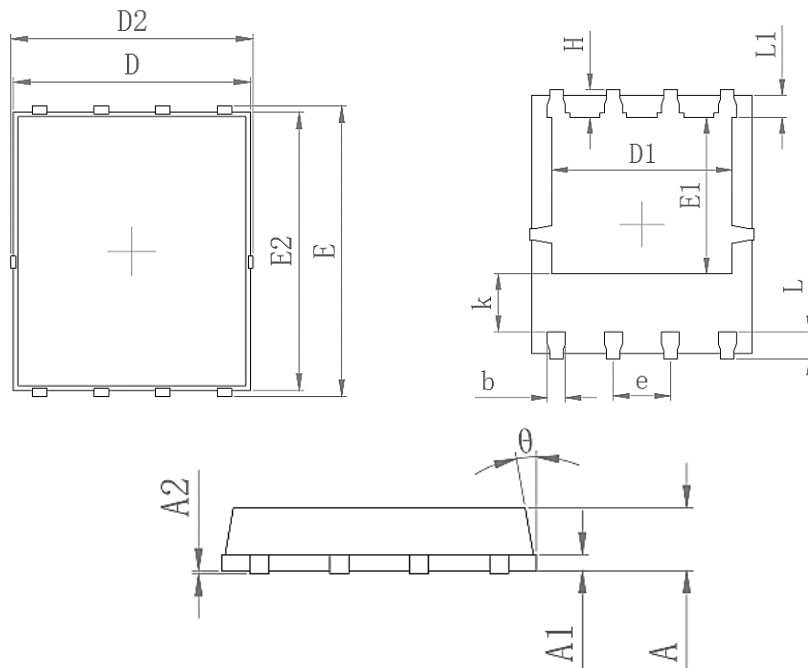


Figure 11. Normalized Maximum Transient Thermal Impedance

### Package Mechanical Data-PDFN5X6-8L-XZT Single



Symbol	Common	
	mm	
	Mim	Max
A	0.90	1.10
A1	0.254 REF	
A2	0-0.05	
D	4.824	4.976
D1	3.910	4.110
D2	4.944	5.076
E	5.924	6.076
E1	3.375	3.575
E2	5.674	5.826
b	0.350	0.450
e	1.270	
L	0.534	0.686
L1	0.424	0.576
K	1.190	1.390
H	0.549	0.701
$\Phi$	8°	12°

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Edition	Date	Change
Rve1.0	2021/3/20	Initial release

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